## Supertex inc.



# P-Channel Enhancement-Mode Vertical DMOS FETs

## **Ordering Information**

BV <sub>DSS</sub> /	R <sub>DS(ON)</sub>	I <sub>D(ON)</sub>	Order Number / Package		
BV <sub>DGS</sub>	(max)	(min)	Die <sup>†</sup>		
-60V	8.0Ω	-0.5A	VP1506NW		
-90V	8.0Ω	-0.5A	VP1509NW		

<sup>†</sup> MIL visual screening available.

#### **Features**

- ☐ Free from secondary breakdown
- □ Low power drive requirement
- Ease of paralleling
- Low C<sub>iss</sub> and fast switching speeds
- Excellent thermal stability
- Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-channel devices

#### **Applications**

- Motor controls
- Converters
- Amplifiers
- Switches
- Power supply circuits
- Drivers (relays, hammers, solenoids, lamps, memories, displays, bipolar transistors, etc.)

#### **Absolute Maximum Ratings**

Drain-to-Source Voltage	$BV_{DSS}$		
Drain-to-Gate Voltage	BV <sub>DGS</sub>		
Gate-to-Source Voltage	± 20V		
Operating and Storage Temperature	-55°C to +150°C		
Soldering Temperature*	300°C		

<sup>\*</sup> Distance of 1.6 mm from case for 10 seconds

#### Advanced DMOS Technology

These enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

#### 07/08/02

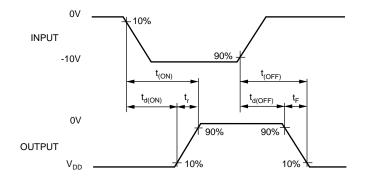
## Electrical Characteristics (@ 25°C unless otherwise specified)

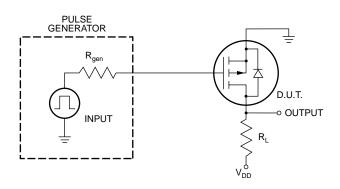
Symbol	Parameter		Min	Тур	Max	Unit	Conditions
BV <sub>DSS</sub>	Drain-to-Source	VP1509	-90				
	Breakdown Voltage	VP1506	-60			V	$I_{D} = -1.0 \text{mA}, V_{GS} = 0 \text{V}$
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.5		-3.5	V	$V_{GS} = V_{DS}$ , $I_D = -1.0$ mA
$\Delta V_{GS(th)}$	Change in V <sub>GS(th)</sub> with Temperature			5.8	6.5	mV/°C	$I_D = -1.0 \text{mA}, V_{GS} = V_{DS}$
I <sub>GSS</sub>	Gate Body Leakage			-1.0	-100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
I <sub>DSS</sub>	Zero Gate Voltage Drain Current				-10	μΑ	$V_{GS} = 0V$ , $V_{DS} = Max$ Rating
					-1	mA	$V_{GS} = 0V$ , $V_{DS} = 0.8$ Max Rating $T_A = 125$ °C
I <sub>D(ON)</sub>	ON-State Drain Current		-0.15	-0.25		Α	$V_{GS} = -5V, V_{DS} = -25V$
			-0.50	-1.2			$V_{GS} = -10V, V_{DS} = -25V$
R <sub>DS(ON)</sub>	Static Drain-to-Source ON-State Resistance			11	15	Ω	$V_{GS} = -5V, I_{D} = -0.1A$
				6.0	8.0		$V_{GS} = -10V, I_D = -0.5A$
$\Delta R_{DS(ON)}$	Change in R <sub>DS(ON)</sub> with Temperature			0.55	1.0	%/°C	$V_{GS} = -10V, I_D = -0.5A$
G <sub>FS</sub>	Forward Transconductance		150	190		mʊ	$V_{DS} = -25V, I_{D} = -0.5A$
C <sub>ISS</sub>	Input Capacitance			45	60		$V_{GS} = 0V, V_{DS} = -25V$
C <sub>OSS</sub>	Common Source Output Capac	citance		22	30	$v_{GS} = 0v, v_{DS} = -25v$ $f = 1 \text{ MHz}$	
C <sub>RSS</sub>	Reverse Transfer Capacitance			3	8		
t <sub>d(ON)</sub>	Turn-ON Delay Time			4	6	V <sub>DD</sub> = -25V	
t <sub>r</sub>	Rise Time			3	10		
t <sub>d(OFF)</sub>	Turn-OFF Delay Time			8	12	ns	$I_D = -0.5A$ $R_{GEN} = 25\Omega$
t <sub>f</sub>	Fall Time			4	10		11GEN - 2032
V <sub>SD</sub>	Diode Forward Voltage Drop		12	-1.2	-2.0	V	I <sub>SD</sub> = -1.0A, V <sub>GS</sub> = 0V
t <sub>rr</sub>	Reverse Recovery Time		JUI	400	TT.	ns	$I_{SD} = -1.0A, V_{GS} = 0V$

#### Notes:

- 1. All D.C. parameters 100% tested at  $25^{\circ}$ C unless otherwise stated. (Pulse test:  $300\mu$ s pulse, 2% duty cycle.)
- 2. All A.C. parameters sample tested.

## **Switching Waveforms and Test Circuit**





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